

L Number	Hits	Search Text	DB	Time stamp
1	187	test near handler and semiconductor adj device	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:35
2	3	test near handler and semiconductor adj device and carrier adj base	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:32
3	6654	Hwang near Hyun Joo.inv.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:33
5	57	Hwang near Hyun .inv.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:33
6	6	Hwang near Hyun .inv. and index near head	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:34
7	0	2002303650.URPN.	USPAT	2004/06/21 11:34
8	34502	test and semiconductor adj device	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:36
9	34502	test and semiconductor adj device elevating near means and head near holder and heating near part	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:36
10	0	test and semiconductor adj device and elevating near means and head near holder and heating near part	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:37
11	64	index near head and 29/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:51
12	1	index near head and 29/\$.ccls. and test near socket	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:57

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12	5	head and 29/\$.ccls. and test near socket and semiconductor and holding and carrier near base	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 12:11
13	33	head and 29/\$.ccls. and test near socket and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 12:41
14	14	("3731191"   "3906363"   "4460236"   "4547964"   "4554506"   "4846702"   "4952872"   "4978912"   "5041183"   "5122070"   "5286944"   "5436570"   "5635849"   "5642056").PN.	USPAT	2004/06/21 12:19
15	69	test adj head near socket and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 12:56
16	18	("3979671"   "4370011"   "4604572"   "4607220"   "4734872"   "4739257"   "4791364"   "4848090"   "4962355"   "4982153"   "5126656"   "5166607"   "5172049"   "5283854"   "5360348"   "5373893"   "5523678"   "5528159").PN.	USPAT	2004/06/21 12:51
17	2	test adj head near socket and semiconductor and 29/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:05
19	0	index adj head near test\$3 and semiconductor and 29/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 12:57
20	3	index adj head near test\$3 and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 12:58
18	13749	index adj head near test\$3and semiconductor and 29/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:05
21	0	test adj head near socket and 29/\$.ccls. and peter near vo .xa.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:05

22	0	test adj head and 29/\$.cccls. and peter near vo .xa.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:06
23	79	test adj head and 29/\$.cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:11
24	23	("3453714"   "3623637"   "3736651"   "4079489"   "4149311"   "4292116"   "4304514"   "4375126"   "4381601"   "4393579"   "4437232"   "4439917"   "4459743"   "4476626"   "4480780"   "4515507"   "4527327"   "4567652"   "4584764"   "4586252"   "4588092"   "4610473"   "4670979").PN.	USPAT	2004/06/21 13:14
25	3	index\$3 near head and testing and handling and 29/\$.cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:12
26	1	index\$3 near head and testing and handling and (219/80; 219/85 ; 219/121EB ; 219/121L ; 219/158 ; 29/593 ; 29/407 ; 29/574).cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:12
27	1	index\$3 near head and testing and (219/80; 219/85 ; 219/121EB ; 219/121L ; 219/158 ; 29/593 ; 29/407 ; 29/574).cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:12
28	5	("4205433"   "4234418"   "4250615"   "4314402"   "4342090").PN.	USPAT	2004/06/21 13:14
29	0	indexing near head and 29/\$.cccls. and 324/\$.cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:15
30	23	test near apparatus and head and 29/\$.cccls. and 324/\$.cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:17
31	241	test near apparatus and head and ( 324/760; 324/765 ; 324/757 ; 324/762 ; 324/755 ; 324/754; 29/874 ; 29/876 ; 438/14).cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:18

32	1	test near apparatus and head and ( 324/760; 324/765 ; 324/757 ; 324/762 ; 324/755 ; 324/754; 29/874 ; 29/876 ; 438/14).ccls. and index and carrier and holder	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 13:18
33	14	("3826984"   "3867698"   "4329642"   "4382228"   "4677474"   "4733172"   "4841231"   "4899099"   "4912399"   "5006792"   "5086269"   "5088190"   "5148103"   "5302891").PN.	USPAT	2004/06/21 13:22
-	2	index adj head near mounting	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/21 11:29
-	3	index adj head and mounting near apparatus	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/18 12:32
-	198	index adj head and apparatus	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/18 12:32
-	9	index adj head and apparatus and semiconductor near device	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/18 12:33
-	19	index adj head and semiconductor near device	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/18 12:35
-	13	index adj head and test near handler	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/18 12:35